

DATA SHEET

74AHC1G07; 74AHCT1G07 Buffer with open-drain output

Product specification
File under Integrated Circuits, IC06

2000 May 02

Buffer with open-drain output

74AHC1G07;
74AHCT1G07

FEATURES

- High noise immunity
- ESD protection:
HBM EIA/JESD22-A114-A exceeds 2000 V
MM EIA/JESD22-A115-A exceeds 200 V
- Low power dissipation
- SOT353 package
- Output capability standard (open drain).

DESCRIPTION

The 74AHC1G/AHCT1G07 is a high-speed Si-gate CMOS device.

The 74AHC1G/AHCT1G07 provides the non-inverting buffer.

The output of the 74AHC1G/AHCT1G07 devices is an open drain and can be connected to other open-drain outputs to implement active-LOW wired-OR or active-HIGH wired-AND functions. For digital operation this device must have a pull-up resistor to establish a logic HIGH-level.

QUICK REFERENCE DATA

GND = 0 V; $T_{amb} = 25\text{ }^{\circ}\text{C}$; $t_r = t_f \leq 3.0\text{ ns}$.

SYMBOL	PARAMETER	CONDITIONS	TYPICAL		UNIT
			AHC1G	AHCT1G	
t_{PZL}	propagation delay inA to outY	$C_L = 15\text{ pF}$; $V_{CC} = 5\text{ V}$	2.5	2.8	ns
t_{PLZ}	propagation delay inA to outY	$C_L = 15\text{ pF}$; $V_{CC} = 5\text{ V}$	4.2	3.9	ns
C_I	input capacitance		1.5	1.5	pF
C_{PD}	power dissipation capacitance	$C_L = 50\text{ pF}$; $f = 1\text{ MHz}$; notes 1 and 2	5.0	6.5	pF

Notes

1. C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

$P_D = C_{PD} \times V_{CC}^2 \times f_i + (C_L \times V_{CC}^2 \times f_o)$ where:

f_i = input frequency in MHz;

f_o = output frequency in MHz;

C_L = output load capacitance in pF;

V_{CC} = supply voltage in Volts.

2. The condition is $V_I = \text{GND to } V_{CC}$.

FUNCTION TABLE

See note 1.

INPUT	OUTPUT
inA	outY
L	L
H	Z

Note

1. H = HIGH voltage level;
L = LOW voltage level;
Z = high impedance OFF-state.

Buffer with open-drain output

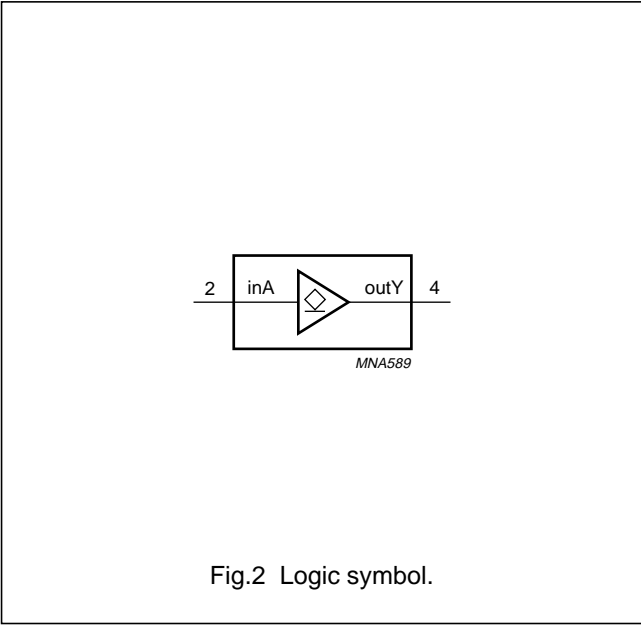
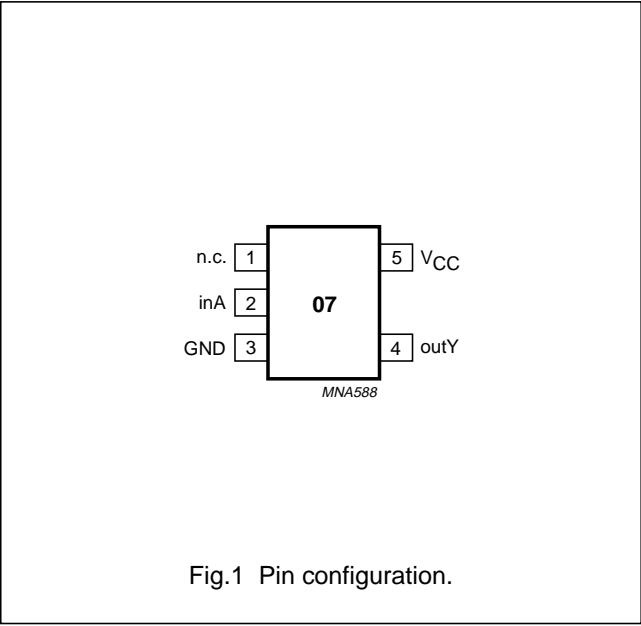
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ORDERING AND PACKAGE INFORMATION

TYPE NUMBER	PACKAGES					
	TEMPERATURE RANGE	PINS	PACKAGE	MATERIAL	CODE	MARKING
74AHC1G07GW	−40 to +125 °C	5	SC-88A	plastic	SOT353	AS
74AHCT1G07GW		5	SC-88A	plastic	SOT353	CS

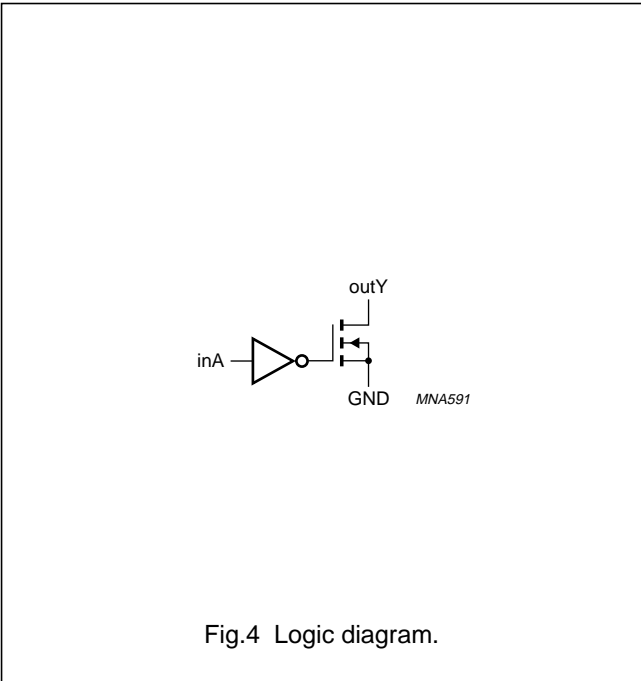
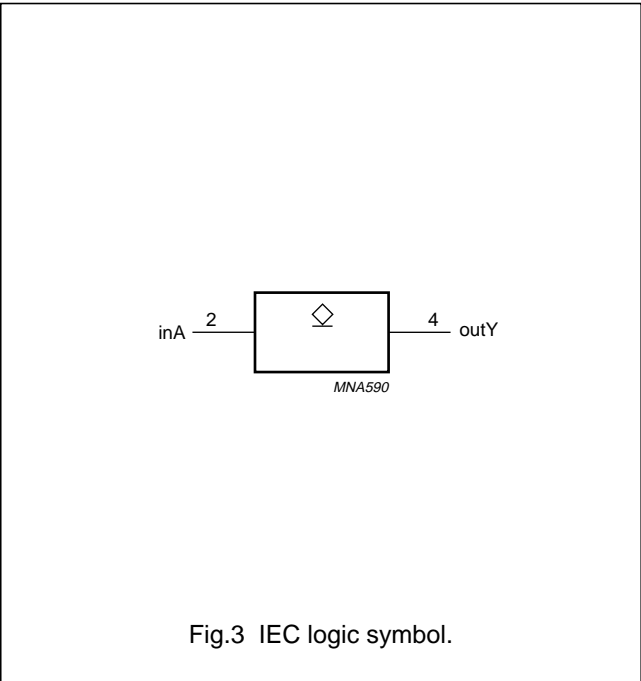
PINNING

SYMBOL	PIN	DESCRIPTION
n.c.	1	not connected
inA	2	data input
GND	3	ground (0 V)
outY	4	data output
V _{CC}	5	DC supply voltage



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RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	74AHC			74AHCT			UNIT
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
V _{CC}	DC supply voltage		2.0	5.0	5.5	4.5	5.0	5.5	V
V _I	input voltage		0	–	5.5	0	–	5.5	V
V _O	output voltage	active mode	0	–	V _{CC}	0	–	V _{CC}	V
		high-impedance mode	0	–	6.0	0	–	6.0	V
T _{amb}	operating ambient temperature	see DC and AC characteristics per device	–40	+25	+85	–40	+25	+85	°C
			–40	+25	+125	–40	+25	+125	°C
t _r , t _f (Δt/Δf)	input rise and fall times ratios (except for Schmitt-trigger inputs)	V _{CC} = 3.3 ±0.3 V	–	–	100	–	–	–	ns/V
		V _{CC} = 5 ±0.5 V	–	–	20	–	–	20	ns/V

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74AHC1G07;
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In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{CC}	DC supply voltage		-0.5	+7.0	V
V_I	input voltage		-0.5	+7.0	V
I_{IK}	DC input diode current	$V_I < -0.5$ V; note 1	–	-20	mA
I_{OK}	DC output clamping diode current	$V_O < -0.5$ V; note 1	–	±20	mA
V_O	output voltage	active mode; note 1	-0.5	$V_{CC} + 0.5$	V
		high-impedance mode; note 1	-0.5	7.0	V
I_O	DC output sink current	$V_O > -0.5$ V	–	±25	mA
I_{CC}	DC V_{CC} or GND current		–	±75	mA
T_{stg}	storage temperature		-65	+150	°C
P_D	power dissipation per package	for temperature range: -40 to +125 °C; note 2	–	200	mW

Notes

1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. Above 55 °C the value of P_D derates linearly with 2.5 mW/K.

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DC CHARACTERISTICS

74AHC1G family

Over recommended operating conditions; voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	TEST CONDITIONS		T _{amb} (°C)							UNIT
		OTHER	V _{CC} (V)	25			–40 to +85		–40 to +125		
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.	MAX.	
V _{IH}	HIGH-level input voltage		2.0	1.5	–	–	1.5	–	1.5	–	V
			3.0	2.1	–	–	2.1	–	2.1	–	V
			5.5	3.85	–	–	3.85	–	3.85	–	V
V _{IL}	LOW-level input voltage		2.0	–	–	0.5	–	0.5	–	0.5	V
			3.0	–	–	0.9	–	0.9	–	0.9	V
			5.5	–	–	1.65	–	1.65	–	1.65	V
V _{OL}	LOW-level output voltage	V _I = V _{IH} or V _{IL} ; I _O = 50 μA	2.0	–	0	0.1	–	0.1	–	0.1	V
			3.0	–	0	0.1	–	0.1	–	0.1	V
			4.5	–	0	0.1	–	0.1	–	0.1	V
		V _I = V _{IH} or V _{IL} ; I _O = 4 mA	3.0	–	–	0.36	–	0.44	–	0.55	V
		V _I = V _{IH} or V _{IL} ; I _O = 8 mA	4.5	–	–	0.36	–	0.44	–	0.55	V
I _I	input leakage current	V _I = V _{CC} or GND	5.5	–	–	0.1	–	1.0	–	2.0	μA
I _{OZ}	3-state output OFF-state current	V _I = V _{IH} or V _{IL} ; V _O = V _{CC} or GND	5.5	–	–	±0.25	–	±2.5	–	±10.0	μA
I _{CC}	quiescent supply current	V _I = V _{CC} or GND; I _O = 0	5.5	–	–	1.0	–	10	–	20	μA
C _I	input capacitance		–	–	1.5	10	–	10	–	10	pF

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Over recommended operating conditions; voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	TEST CONDITIONS		T _{amb} (°C)							UNIT
		OTHER	V _{CC} (V)	25			–40 to +85		–40 to +125		
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.	MAX.	
V _{IH}	HIGH-level input voltage		4.5 to 5.5	2.0	–	–	2.0	–	2.0	–	V
V _{IL}	LOW-level input voltage		4.5 to 5.5	–	–	0.8	–	0.8	–	0.8	V
V _{OL}	LOW-level output voltage	V _I = V _{IH} or V _{IL} ; I _O = 50 μA	4.5	–	0	0.1	–	0.1	–	0.1	V
		V _I = V _{IH} or V _{IL} ; I _O = 8 mA	4.5	–	–	0.36	–	0.44	–	0.55	V
I _I	input leakage current	V _I = V _{CC} or GND	5.5	–	–	0.1	–	1.0	–	2.0	μA
I _{OZ}	3-state output OFF-state current	V _I = V _{IH} or V _{IL} ; V _O = V _{CC} or GND	5.5	–	–	±0.25	–	±2.5	–	±10.0	μA
I _{CC}	quiescent supply current	V _I = V _{CC} or GND; I _O = 0	5.5	–	–	1.0	–	10	–	20	μA
ΔI _{CC}	additional quiescent supply current per input pin	V _I = 3.4 V; other inputs at V _{CC} or GND; I _O = 0	4.5 to 5.5	–	–	1.35	–	1.5	–	1.5	mA
C _I	input capacitance		–	–	1.5	10	–	10	–	10	pF

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AC CHARACTERISTICS

Type 74AHC1G07

GND = 0 V; $t_r = t_f \leq 3.0$ ns.

SYMBOL	PARAMETER	TEST CONDITIONS		T _{amb} (°C)						UNIT		
		WAVEFORMS	C _L	25			–40 to +85		–40 to +125			
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.		MAX.	
V _{CC} = 3.0 to 3.6 V; note 1												
t _{PZL}	propagation delay inA to outY	see Figs 5 and 6	15 pF	–	3.5	5.6	1.0	6.3	1.0	7.0	ns	
t _{PLZ}				–	5.8	7.9	1.0	8.4	1.0	8.9	ns	
t _{PZL}	propagation delay inA to outY	see Figs 5 and 6	50 pF	–	5.0	8.0	1.0	9.0	1.0	10.0	ns	
t _{PLZ}				–	8.3	11.5	1.0	12.0	1.0	12.5	ns	
V _{CC} = 4.5 to 5.5 V; note 2												
t _{PZL}	propagation delay inA to outY	see Figs 5 and 6	15 pF	–	2.5	3.9	1.0	4.6	1.0	4.9	ns	
t _{PLZ}				–	4.2	5.1	1.0	5.6	1.0	6.1	ns	
t _{PZL}	propagation delay inA to outY	see Figs 5 and 6	50 pF	–	3.6	5.5	1.0	6.5	1.0	7.0	ns	
t _{PLZ}				–	6.0	7.5	1.0	8.0	1.0	8.5	ns	

Notes

1. Typical values at $V_{CC} = 3.3$ V.
2. Typical values at $V_{CC} = 5.0$ V.

Type 74AHCT1G07

GND = 0 V; $t_r = t_f \leq 3.0$ ns.

SYMBOL	PARAMETER	TEST CONDITIONS		T _{amb} (°C)								UNIT
		WAVEFORMS	C _L	25			−40 to +85		−40 to +125			
				MIN.	TYP.	MAX.	MIN.	MAX.	MIN.	MAX.		
V _{CC} = 4.5 to 5.5 V; note 1												
t _{PZL}	propagation delay inA to outY	see Figs 5 and 6	15 pF	–	2.8	4.6	1.0	5.3	1.0	5.6	ns	
t _{PLZ}				–	3.9	5.6	1.0	6.1	1.0	6.6	ns	
t _{PZL}	propagation delay inA to outY	see Figs 5 and 6	50 pF	–	4.0	6.5	1.0	7.5	1.0	8.0	ns	
t _{PLZ}				–	5.5	8.0	1.0	8.5	1.0	9.0	ns	

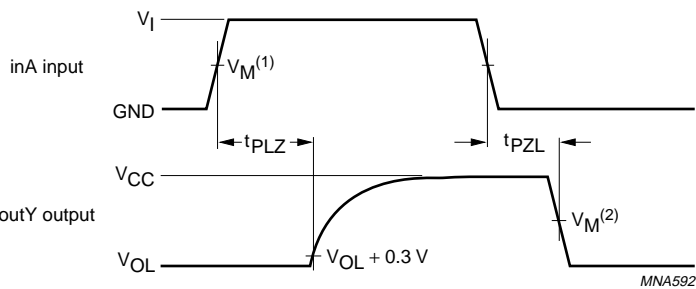
Note

1. Typical values at $V_{CC} = 5.0$ V.

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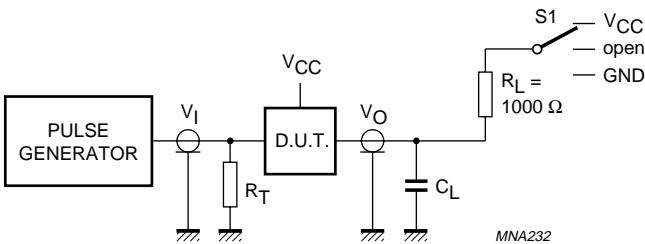
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AC WAVEFORMS



FAMILY	V_I INPUT REQUIREMENTS	$V_M^{(1)}$ INPUT	$V_M^{(2)}$ OUTPUT
AHC1G	GND to V_{CC}	50% V_{CC}	50% V_{CC}
AHCT1G	GND to 3.0 V	1.5 V	50% V_{CC}

Fig.5 The input inA to output outY propagation delays.



TEST	S1
t_{PLH}/t_{PHL}	open
t_{PLZ}/t_{PZL}	V_{CC}
t_{PHZ}/t_{PZH}	GND

Definitions for test circuit:
 C_L = Load capacitance including jig and probe capacitance (see Chapter “AC characteristics”).
 R_T = Termination resistance should be equal to the output impedance Z_0 of the pulse generator.

Fig.6 Load circuitry for switching times.

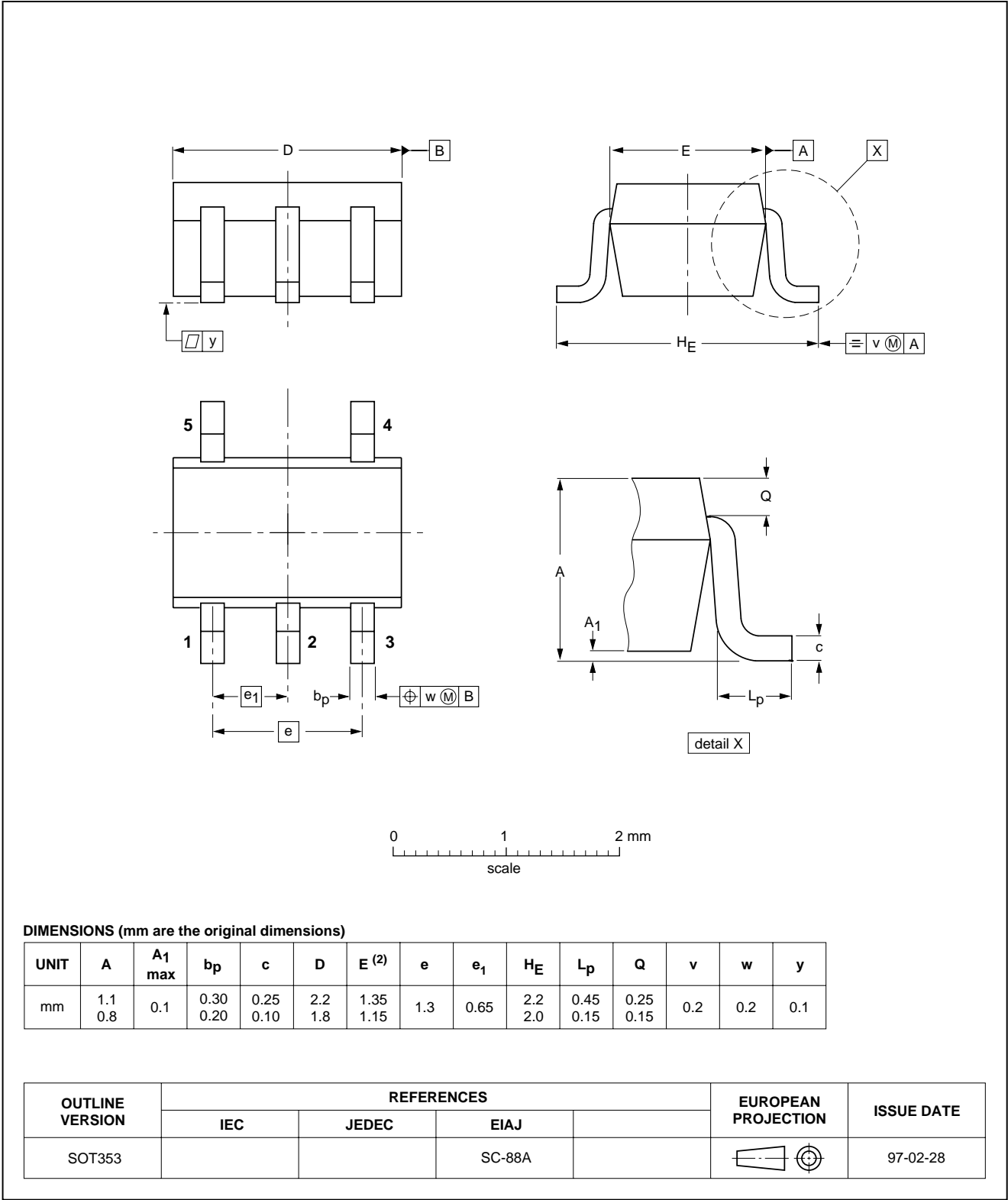
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PACKAGE OUTLINE

Plastic surface mounted package; 5 leads

SOT353



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SOLDERING

Introduction to soldering surface mount packages

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our *"Data Handbook IC26; Integrated Circuit Packages"* (document order number 9398 652 90011).

There is no soldering method that is ideal for all surface mount IC packages. Wave soldering is not always suitable for surface mount ICs, or for printed-circuit boards with high population densities. In these situations reflow soldering is often used.

Reflow soldering

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement.

Several methods exist for reflowing; for example, infrared/convection heating in a conveyor type oven. Throughput times (preheating, soldering and cooling) vary between 100 and 200 seconds depending on heating method.

Typical reflow peak temperatures range from 215 to 250 °C. The top-surface temperature of the packages should preferably be kept below 230 °C.

Wave soldering

Conventional single wave soldering is not recommended for surface mount devices (SMDs) or printed-circuit boards with a high component density, as solder bridging and non-wetting can present major problems.

To overcome these problems the double-wave soldering method was specifically developed.

If wave soldering is used the following conditions must be observed for optimal results:

- Use a double-wave soldering method comprising a turbulent wave with high upward pressure followed by a smooth laminar wave.
- For packages with leads on two sides and a pitch (e):
 - larger than or equal to 1.27 mm, the footprint longitudinal axis is **preferred** to be parallel to the transport direction of the printed-circuit board;
 - smaller than 1.27 mm, the footprint longitudinal axis **must** be parallel to the transport direction of the printed-circuit board.

The footprint must incorporate solder thieves at the downstream end.

- For packages with leads on four sides, the footprint must be placed at a 45° angle to the transport direction of the printed-circuit board. The footprint must incorporate solder thieves downstream and at the side corners.

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Typical dwell time is 4 seconds at 250 °C.

A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

Manual soldering

Fix the component by first soldering two diagonally-opposite end leads. Use a low voltage (24 V or less) soldering iron applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to 300 °C.

When using a dedicated tool, all other leads can be soldered in one operation within 2 to 5 seconds between 270 and 320 °C.

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Suitability of surface mount IC packages for wave and reflow soldering methods

PACKAGE	SOLDERING METHOD	
	WAVE	REFLOW ⁽¹⁾
BGA, LFBGA, SQFP, TFBGA	not suitable	suitable
HBCC, HLQFP, HSQFP, HSOP, HTQFP, HTSSOP, SMS	not suitable ⁽²⁾	suitable
PLCC ⁽³⁾ , SO, SOJ	suitable	suitable
LQFP, QFP, TQFP	not recommended ⁽³⁾⁽⁴⁾	suitable
SSOP, TSSOP, VSO	not recommended ⁽⁵⁾	suitable

Notes

1. All surface mount (SMD) packages are moisture sensitive. Depending upon the moisture content, the maximum temperature (with respect to time) and body size of the package, there is a risk that internal or external package cracks may occur due to vaporization of the moisture in them (the so called popcorn effect). For details, refer to the Drypack information in the *"Data Handbook IC26; Integrated Circuit Packages; Section: Packing Methods"*.
2. These packages are not suitable for wave soldering as a solder joint between the printed-circuit board and heatsink (at bottom version) can not be achieved, and as solder may stick to the heatsink (on top version).
3. If wave soldering is considered, then the package must be placed at a 45° angle to the solder wave direction. The package footprint must incorporate solder thieves downstream and at the side corners.
4. Wave soldering is only suitable for LQFP, TQFP and QFP packages with a pitch (e) equal to or larger than 0.8 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.65 mm.
5. Wave soldering is only suitable for SSOP and TSSOP packages with a pitch (e) equal to or larger than 0.65 mm; it is definitely not suitable for packages with a pitch (e) equal to or smaller than 0.5 mm.

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DATA SHEET STATUS

DATA SHEET STATUS	PRODUCT STATUS	DEFINITIONS ⁽¹⁾
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

Note

1. Please consult the most recently issued data sheet before initiating or completing a design.

DEFINITIONS

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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NOTES

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NOTES

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